WAN Tester I

- Tests asynchronous, synchronous, T-1, fractional T-1, E-1 and fractional E-1 facilities and equipment
- V.35, RS232, RS422/RS530, X.21, T-1 and E-1 interfaces
- Data rates from 50 bps to 2.048 Mbps
- Built-in speaker for monitoring DS0s or timeslots
- Displays G.821 performance measurements
- Terminate and Monitor
- Front Panel, VT100 console control or Command Line Interface
- AC or battery power

The Telinc WAN Tester is a sophisticated bit error rate tester in a compact, hand held package. It can test a wide variety of communications facilities and equipment including T-1, fractional T-1, E-1, fractional E-1, modems, multiplexers, CSU/DSUs, T-1 ESF CSUs, DU, NTUs and TIUs. It is supplied complete with V.35, RS232, RS422/RS530, X.21, DS1 (T-1, 1.544 Mbps) and G.703 (E-1, 2.048 Mbps) interfaces.

The Tester is supplied with a wall-mounted AC transformer. A battery option is also available for complete portable operation. With the option, a nickel metal hydride battery and a recharger are built into the Tester.

T-1 and E-1 Testing

The user can choose from four operating modes: T-1, E-1, asynchronous and synchronous. A variety of test patterns can be inserted in all or selected time slots/DS0s, continuous or non-contiguous, making the Tester ideal for fractional T-1 and E-1 testing.

In the T-1 and E-1 modes, the WAN Tester counts and displays bit errors, transmit and receive frequency, test seconds, bit error rate, and G.821 performance measurements (errored seconds, severely errored seconds, degraded minutes and available and unavailable times). In the T-1 mode it also displays receive level.

Asynchronous and Synchronous Testing

In addition to T-1 and E-1, the WAN Tester provides asynchronous and synchronous test modes. It generates test data in a choice of patterns and formats. The user can choose from a selection of twenty-eight asynchronous and seventy-five synchronous test speeds.

The Tester counts and displays bit errors, bit error rate, and total test seconds. In the asynchronous mode, it also counts and displays characters received, character errors and errored seconds. In the synchronous mode, it also displays transmit frequency, receive frequency, clear to send delay and G.821 performance measurements.

Easy to use

The WAN Tester I can be controlled from the front panel or from a local or remote VT100 terminal. It includes a two-line LCD display and sixteen indicator lights that show selected mode, test and operating parameters. Parameters are selected by scrolling through values stored in the Tester. All operations can be performed using only ten keys.

WAN Tester I

Specifications

ASYNC

Speeds:	50 to 115,000 bps
Displays:	Character Errors, Characters Received, Total Test Seconds, Errored Seconds, Round Trip Delay and Elapsed Time
LEDS:	Pattern Lock, Pattern Recovered, TXD, RXD, RTS, CTS, DSR, CD, and DTR
Patterns:	2^9 (511), 2^11 (2047), Binary, Fox Test, Mark, Space and Round Trip Delay
Loops:	Self-Test
Interfaces:	V.35, RS530, RS422 and RS232 Physical: DB 25 pin Female

SYNC

Speeds:	1,200 to 50,000,000 bps
Displays:	Bit Errors, Bit Error Rate, Test Secs, Errored Secs, Severely Errored Secs, Degraded Mins, Available, Unavailable, RX Freq, TX Freq, Bits Received, RTS Time, Round Trip Delay and Elapsed Time
LEDS:	Pattern Lock, Pattern Recovered, Transmit Data, Receive Data, RTS (C), CTS, DSR, CD (I), DTR, TXC, RXC (S), and External TXC
Patterns:	2^9 (511), 2^11 (2047), 2^15, ITU 2^15, QRSS, 2^20, ITU 2^20, 2^23, ITU 2^23, 1 of 8, 3 of 24, Alt, Mark, Space and Round Trip Delay
Loops:	Self-Test and V.54
Interfaces:	V.35/DB25, RS530/DB25, RS422/DB25, RS232/DB25, and X.21/DB15 pin

T-1

Speed:	1,544,000 bps
Displays:	Bit Errors, Bit Error Rate, Test Secs, Errored Secs, Severely Errored Secs, Degraded Mins, Available, Unavailable, RX Freq, TX Freq, Signalling Bits, Density Errs, Frame Errs, CRC Err, BPV Err, RX Level Volts & dB, Slips, Round Trip Delay
LEDS:	Pattern Lock, Pattern Recovered, Frame Lock, AIS (Blue), RLOS, CRC Err, BPV, D4, ESF, AMI, B8ZS and Yellow
Patterns:	2^9 (511), 2^11 (2047), 2^15, ITU 2^15, QRSS, 2^20, ITU 2^20, 2^23, ITU 2^23, 1 of 8, 3 of 24, T-1 DALY, T-1 DALY UF, 55 Octet, 55 Octet UF, Alt, Mark, Space , Digimwatt, User 3 - 32, Round Trip Delay, DDS OCU Loop, DDS CSU Loop and DDS DSU Loop
Loops:	Self-Test, ATT Loop U/D, ANSI Loop U/D, ATT Payload, ANSI Payload, Smart Jack 1 & 2 (Framed & Unframed) and V.54
Speaker:	Monitors selected TX or RX DS0 for voice
Interfaces:	DS1 BiPolar, 110 Ohm, AMI/B8ZS Coding Physical: RJ48C and Dual Bantam

E-1

Speed:	2,048,000 bps
Displays:	Bit Errors, Bit Error Rate, Test Secs, Errored Secs, Severely Errored Secs, Degraded Mins, Available, Unavailable, RX Freq, TX Freq, Slips, CRC Errs, BPV Errs and Frame Errs
LEDS:	Pattern Lock, Pattern Recovered, Frame Lock, AIS (Blue), RLOS, CRC Err, BPV, DMFA and RRA
Patterns:	2^9 (511), 2^11 (2047), 2^15, ITU 2^15, QRSS, 2^20, ITU 2^20, 2^23, ITU 2^23, 1 of 8, 3 of 24, Alt, Mark, Space, Digimwatt and User 3 - 32
Loops:	Self-Test and V.54
Speaker:	Monitors selected TX or RX timeslot for voice
Interfaces:	G.703/704, 75 & 120 Ohm, HDB3 Coding Physical: Dual Bantam, Dual BNC and RJ48C

Physical

Mechanical:	The WAN Tester I measures 5" (12.7 cm) H x 7" (17.8 cm) W x 2" (5.1 cm) D and weighs 1 lb (.45 kg)

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